PCN Number:	20150317004A PCN Date: 05/14/2015							05/14/2015	
Title: DLPA3000 & DLPA3005 A3 Redesign									
Customer Contact: Dlp_pcn_team@list.ti.com Dept: DLP® CQE									
			<mark>1, 2015</mark>		Estimated S		ample	ample May 5, 2015	
Change Type:									
Assembly Sit	<u> </u>		X D	esign			Wafe	r Bum	np Site
Assembly Process		Data Sheet		t		_	er Bump Material		
Assembly Materials		Part numb			change		Wafer Bump Process		
Mechanical Specification		Test Site					Wafer Fab Site		
Packing/Shipping/Labeling		Test Process		SS		Wafe	Wafer Fab Materials		
							Wafer Fab Process		
PCN Details									
Description of Change:									
	Revision A is to inform customers of corrected sample and proposed ship date. Please see							<mark>Please see</mark>	
above.	above.								
	_					_			6.1
Texas Instrument				incing ini	tial notificati	on for	qualific	ation	of the
DLPA3000 & DLPA	DLPA3000 & DLPA3005 A3 Re-design.								
*First Shin Date i	*First Ship Date is based on the scheduled Qualification plan completion date. The First Ship								
Date will be updated on the Final PCN based on the actual Qualification plan completion date. Reason for Change:									
	Design Enhancements								
-Low Vin to allow 6VIN , supports dual battery implementations.									
	-High Vin to allow +20VIN FOR PAD 3000								
- Activate all 3GP ANC Bucks									
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):									
Additional Functions - See Reasons for Change section directly above.									
Changes to product identification resulting from this PCN:									
The part will be m									
Example:									
 Current Marking DLPA3000C will become DLPA3000D 									
 Current Marking DLPA3005C will become DLPA3005D 									
Product Affected:									
DLPA3000CPFD, DLPA3000CPFDR, DLPA3005CPFD, DLPA3005CPFDR, PAD3000A2PFD,									
PAD3000A2PFDR, PAD3005A2PFD, PAD3005A2PFDR									
Qualification Plan									
This qualification has been developed for the validation of this change. The qualification data									
validates that the proposed change meets the applicable released technical specifications.									
Qualification Sc	hedule:	St	art:	May 2	5, 2015		End:	Ju	ne 25, 2015
Qual Vehicle: Device Vehicle (DLPA3000D & DLPA3005D)									

Qualification: \square **Plan** \square **Test Results**

Qualification Plan

Test	Conditions	Read Points	Sample Size
A. Life Test:			
High Temperature Operating Life	140C	480 hours	QBS(1)
B. Environmental Tests:			
Preconditioning + Temperature Cycling:			
(a) Preconditioning	MSL2; 85C/60%RH	168hrs	QBS(1)
(b) Temperature Cycling	-65C/+150C	500 cycles	
ESD	НВМ	+/- 2000V	QBS(1)
ESD	CDM	+/- 750V	QBS(1)
Electrical Characterization	Per data sheet		30 (each)
Latch Up	70C	+/- 100mA	QBS(1)
C. Inspection Tests:			
X-Ray	Top view only		QBS(1)
D. Other			
Manufacturing Qual	TITL ERTP		1 lot (each)

Notes:

1) QBS (Qual by Similarity) to DLPA3000C

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
DLP PCN Team	dlp pcn team@ti.com
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com